

SUCCESS IS BEING EXCELLENT AT WHAT YOU DO

Learn how to get the most from your PDF-4+ database from the database experts.

Join ICDD at our free PDF-4+ users meeting during the
59th Annual Denver X-ray Conference!

August Users Meeting

Sunday, 1 August 2010

Denver X-ray Conference 2010

Denver Marriott Tech Center Hotel

Denver, Colorado

10:00 a.m.—4:00 p.m.

Register by 25 July

International Centre for Diffraction Data

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Getting Started Tutorial

This tutorial will discuss and demonstrate the basic functions of DDView+, thus enabling the user to distill the huge number of entries in PDF-4+ to a manageable selected subset.

- ▲ Selecting search criteria for up to 53 unique Search Fields
- ▲ Viewing/analyzing search results
- ▲ Using History and standard formats to optimize your searches
- ▲ Using digital patterns for data simulations and analysis

Advanced Features Tutorial

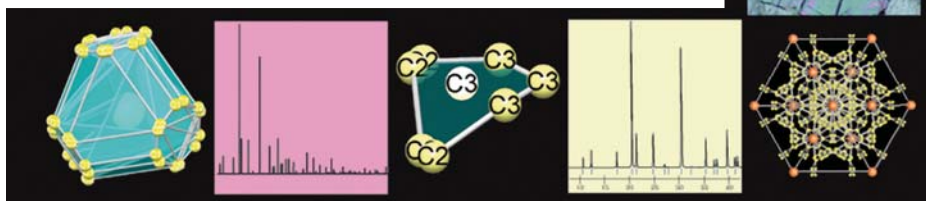
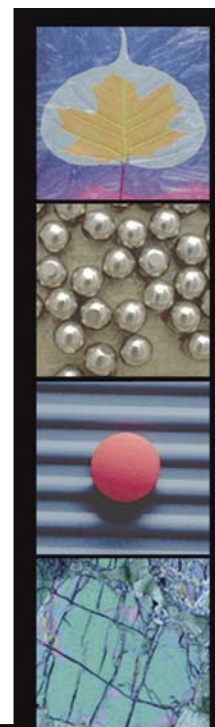
This tutorial focuses on the power of DDView+ and SLeve+ for phase identification, simulation of X-ray, neutron, and electron diffraction patterns, and retrieval/use of PDF-4+ database information for advanced analyses.

- ▲ Performing neutron, electron, EBSD, spot pattern simulations
- ▲ Advanced data mining — tools to extract the data you need
- ▲ Using SLeve+ — choosing the appropriate search criteria and strategies for identification and problem analysis
- ▲ Interfaces — Using PDF-4+ information as input for advanced analyses (whole-pattern fitting, structure analysis, molecular visualization, cluster analysis)

Problem Solving Examples

- ▲ Published solutions to difficult problems using PDF-4+

Register online at www.icdd.com/education/usersmeeting.asp



2010 PDF-4+ Users Meeting

Registration Form

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Please choose up to three topics. We will focus our time on the most requested topics.

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- Published solutions to difficult problems using PDF-4 +

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- | | | | |
|-------------------------------------|--------------------|---|--------------------|
| <input type="checkbox"/> PDF-2 | Release Year _____ | <input type="checkbox"/> PDF-4 + | Release Year _____ |
| <input type="checkbox"/> DDView | Release Year _____ | <input type="checkbox"/> PDF-4/Organics | Release Year _____ |
| <input type="checkbox"/> ICDD SUITE | Release Year _____ | <input type="checkbox"/> Sleeve + | Release Year _____ |

Interests (please circle):

XRD	Corrosion	Minerals	Synchrotron
XRF	Electron Diffraction	Pharmaceutical	Other (please specify):
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